




<p>Searched</p> 	<p>Application/Control No.</p> <p>10811403</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>CHEN ET AL.</p>
	<p>Examiner</p> <p>Tran, Mai T</p>	<p>Art Unit</p> <p>2129</p>

Class	SubClass	Date	Examiner
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Search Notes 	Application/Control No. 10811403	Applicant(s)/Patent Under Reexamination CHEN ET AL.
	Examiner Tran, Mai T	Art Unit 2129

Notes	Date	Examiner
EAST (Please see search history printout)	9/22/2006	mtt
ACM Portal (Please see search history printout)	9/22/2006	mtt
Google (Please see search history printout)	9/22/2006	mtt
IEEE (Please see search history printout)	9/22/2006	mtt
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